

January 1993 Revised November 1999

74ABT377 Octal D-Type Flip-Flop with Clock Enable

General Description

The ABT377 has eight edge-triggered, D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) input loads all flip-flops simultaneously when the Clock Enable (CE) is LOW.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output. The $\overline{\text{CE}}$ input must be stable only one setup time prior to the LOW-to-HIGH clock transition for predictable operation.

Features

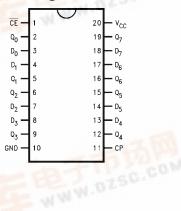
- Clock enable for address and data synchronization applications
- Eight edge-triggered D-type flip-flops
- Buffered common clock
- See ABT273 for master reset version
- See ABT373 for transparent latch version
- See ABT374 for 3-STATE version
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability
- Disable time less than enable time to avoid bus

Ordering Code:

Order Number	Package Number	Package Description
74ABT377CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ABT377CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT377CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74ABT377CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Pin Descriptions

Pin Names	Descriptions
D ₀ -D ₇	Data Inputs
CE	Clock Enable (Active LOW)
CP	Clock Pulse Input
Q ₀ –Q ₇	Data Outputs

Truth Table

i	Operating Mode	Inputs			Output
ŀ		СР	CE	D _n	Q _n
	Load "1"	~	I	h	Н
	Load "0"	~	I	I	L
	Hold	~	h	Χ	No Change
	(Do Nothing)	Х	Н	Χ	No Change

- H = HIGH Voltage Level
- L = LOW Voltage Level ✓ = LOW-to-HIGH Clock Transition = Immaterial
- HIGH Voltage Level one setup time prior to the LOW-to-HIGH Clock Transition
- LOW Voltage Level one setup time prior to the LOW-to-HIGH Clock Transition



Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

Storage Temperature -65°C to +150°C -55°C to +125°C Ambient Temperature under Bias

Free Air Ambient Temperature -40°C to +85°C Junction Temperature under Bias $-55^{\circ}C$ to $+150^{\circ}C$ +4.5V to +5.5V Supply Voltage

V_{CC} Pin Potential to Ground Pin -0.5V to +7.0VMinimum Input Edge Rate (ΔV/Δt)

Input Voltage (Note 2) -0.5V to +7.0V Data Input 50 mV/ns Input Current (Note 2) -30 mA to +5.0 mA Enable Input 20 mV/ns

Voltage Applied to Any Output

in the Disabled or

Power-OFF State -0.5V to +4.75V in the HIGH State -0.5V to V_{CC}

in LOW State (Max)

Current Applied to Output

DC Latchup Source Current

Twice the rated I_{OL} (mA)

-500 mA

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied. Note 2: Either voltage limit or current limit is sufficient to protect inputs

(Across Comm Operating Range)

Over Voltage Latchup $V_{CC} + 4.5V$

DC Electrical Characteristics

Symbol	Parameter	Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage			8.0	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage	2.5			V	Min	I _{OH} = -3 mA
		2.0			· ·	IVIIII	$I_{OH} = -32 \text{ mA}$
V _{OL}	Output LOW Voltage			0.55	V	Min	I _{OL} = 64 mA
I _{IH}	Input HIGH Current			1		Max	V _{IN} = 2.7V (Note 3)
				1	μΑ	IVIAX	$V_{IN} = V_{CC}$
I _{BVI}	Input HIGH Current			7	μА	Max	V _{IN} = 7.0V
	Breakdown Test			,	μΑ	IVIAX	VIN = 7.0V
I _{IL}	Input LOW Current			-1	μА	Max	V _{IN} = 0.5V (Note 3)
				-1	μΛ	IVIAX	$V_{IN} = 0.0V$
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA
							All Other Pins Grounded
Ios	Output Short-Circuit Current	-100		-275	mA	Max	V _{OUT} = 0.0V
I _{CEX}	Output HIGH Leakage Current			50	μΑ	Max	V _{OUT} = V _{CC}
I _{CCH}	Power Supply Current			50	μА	Max	All Outputs HIGH
I _{CCL}	Power Supply Current			30	mA	Max	All Outputs LOW
I _{CCT}	Maximum I _{CC} /Input Outputs Enabled						V _I = V _{CC} - 2.1V
				1.5	mA	Max	Data Input V _I = V _{CC} - 2.1V
							All Others at V _{CC} or GND
I _{CCD}	Dynamic I _{CC} No Load			0.3	mA/	Max	Outputs Open (Note 4)
					MHz		One bit Toggling, 50% Duty Cycle

Note 3: Guaranteed but not tested.

Note 4: For 8 bits toggling, $I_{CCD} < 0.5 \text{ mA/MHz}.$

AC Electrical Characteristics

<u> </u>	AC Electrical Characteristics (SOIC Package)									
Symbol	Parameter	$T_A = +25^{\circ}\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50 \text{ pF}$			$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_L = 50 \text{ pF}$		Units			
		Min	Тур	Max	Min	Max				
f _{MAX}	Maximum Clock Frequency	150	200		150		MHz			
t _{PLH}	Propagation Delay	2.2		6.0	2.2	6.0	ns			
t _{PHL}	CP to O _n	2.8		6.8	2.8	6.8	115			

AC Operating Requirements

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_L = 50 \text{ pF}$		V _{CC} = 4.5V to 5.5V		Units
		Min	Max	Min	Max			
t _S (H)	Setup Time, HIGH	2.0		2.0		ns		
t _S (L)	or LOW D _n to CP	2.0		2.0		115		
t _H (H)	Hold Time, HIGH	1.8		1.8		no		
t _H (L)	or LOW D _n to CP	1.8		1.8		ns		
t _S (H)	Setup Time, HIGH	3.0		3.0				
$t_S(L)$	or LOW CE to CP	3.0		3.0		ns		
t _H (H)	Hold Time, HIGH	1.0		1.0				
t _H (L)	or LOW CE to CP	1.0		1.0		ns		
t _W (H)	Pulse Width, CP,	3.3		3.3		ns		
t _W (L)	HIGH or LOW	3.3		3.3		115		

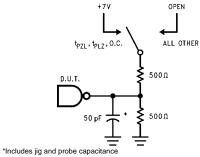
Capacitance

(SOIC Package) (Note 5)

(Color dollage) (Note o)					
	Symbol	Parameter	Тур	Units	Conditions
	C _{IN}	Input Capacitance	5	pF	$V_{CC} = 0V, T_A = 25^{\circ}C$
	COLIT (Note 5)	Output Capacitance	9	pF	$V_{CC} = 5.0V$

Note 5: C_{OUT} is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.

AC Loading



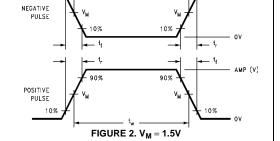


FIGURE 1. Standard AC Test Load

Input Pulse Requirements

Amplitude	Rep. Rate	t _W	t _r	t _f
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

90%

FIGURE 3. Test Input Signal Requirements

AC Waveforms

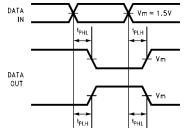


FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

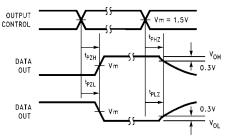


FIGURE 6. 3-STATE Output HIGH and LOW Enable and Disable Times

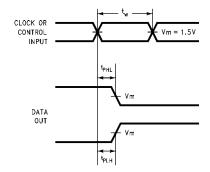


FIGURE 5. Propagation Delay, Pulse Width Waveforms

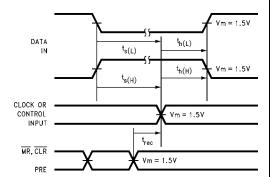
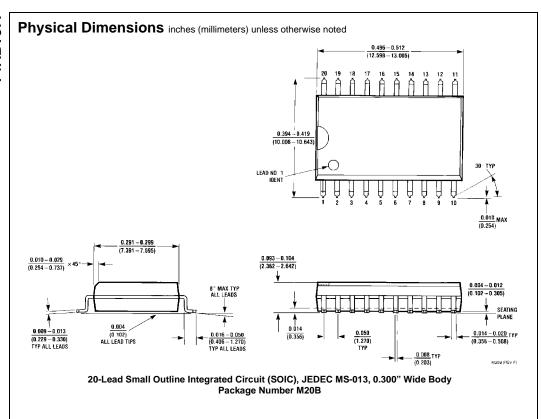
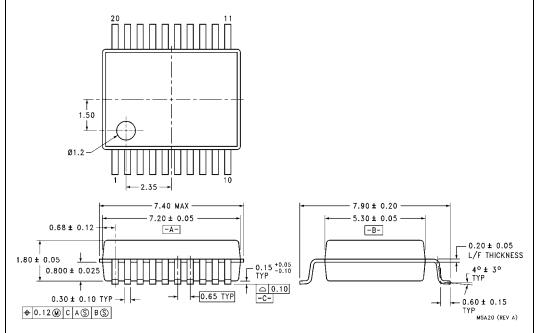


FIGURE 7. Setup Time, Hold Time and Recovery Time Waveforms

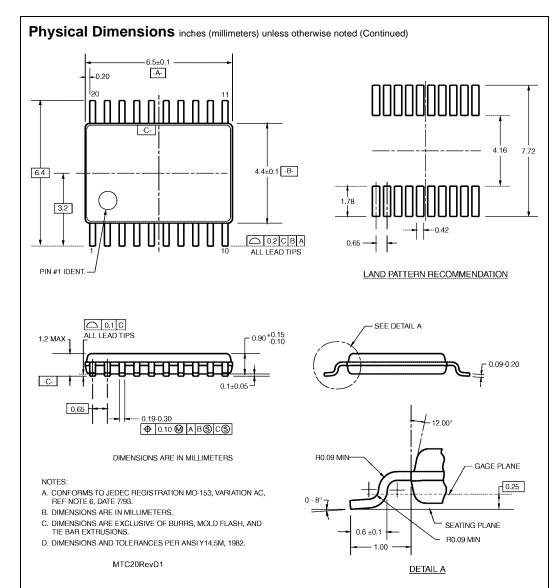


Physical Dimensions inches (millimeters) unless otherwise noted (Continued) -A-5.3±0.10 9.27 TYP 7.8 -B-0.2 C B A ALL LEAD TIPS 10 PIN #1 IDENT.-0.6 TYP 1.27 TYP LAND PATTERN RECOMMENDATION ALL LEAD TIPS SEE DETAIL A 0.1 C 2.1 MAX. 1.8±0.1 L 0.15±0.05 0.15-0.25 -0.35-0.51 **⊕** 0.12 **⋈** C A 1.27 TYP 7° TYP DIMENSIONS ARE IN MILLIMETERS GAGE PLANE NOTES: A. CONFORMS TO EIAJ EDR-7320 REGISTRATION, ESTABLISHED IN DECEMBER, 1998. B. DIMENSIONS ARE IN MILLIMETERS. C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS. 0.60±0.15 SEATING PLANE 1.25 -M20DRevB1 DETAIL A 20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M20D

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20

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